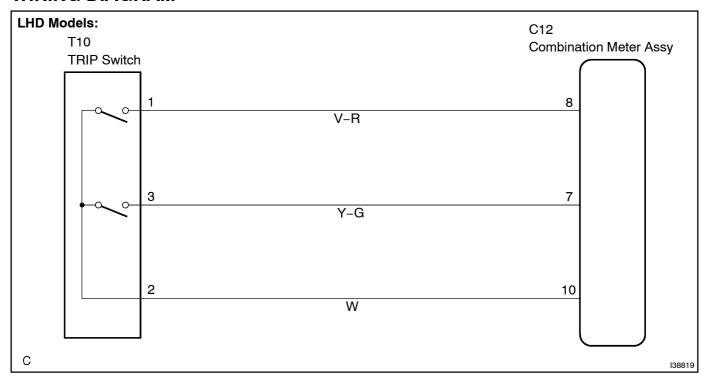
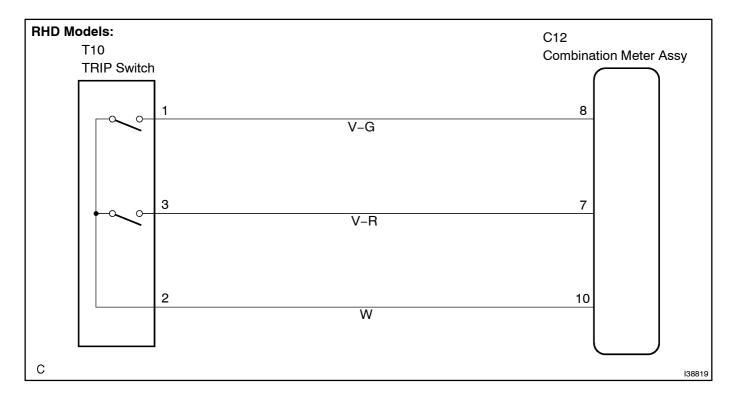
MALFUNCTION IN ODO/TRIP SW

WIRING DIAGRAM





INSPECTION PROCEDURE

1 | READ[VALUE[OF[]NTELLIGENT[]TESTER[]I

(a) Operate the intelligent tester to according to the steps on the display and select the DATA LIST". **METER:**

ltem	Measurement[]tem/ Range[[Display)	Normal[Condition	Diagnostic[Note
ODO/TRIP[\$W	ODO/TRIP[\$witch[]s[]ON[][]DFF	ON:[\$witch[]s[]pushed OFF:[\$witch[]s[]eleased	-
Trip[Reset[\$W	Trip[Reset[\$witch[]s[DN]][DFF	ON:[\$witch[]s[]pushed OFF:[\$witch[]s[]eleased	-

OK:

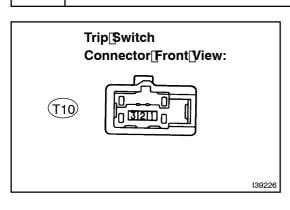
Switchcondition(ON/OFF)can(be(switched(by(actual(operation.

NG Go to step 2

OK

REPLACE[COMBINATION[METER[ASSY(SEE[PAGE[71-21)

2 INSPECT TRIP SWITCH



- (a) Disconnect the trip switch connector.
- (b) Measure the resistance according to the value(s) in the table below.

Standard:

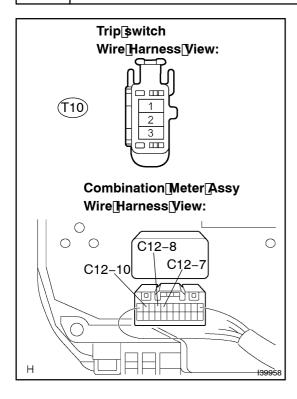
Terminal No	Condition	Specified condition
T10-1 - T10-2	ODO/TRIP switch OFF → ON	10 k Ω or higher → Below 1 Ω
T10-3 - T10-2	RESET switch OFF → ON	10 k Ω or higher → Below 1 Ω

NG)

REPLACE TRIP SWITCH

OK

3 CHECK[HARNESS[AND[CONNECTOR(TRIP[SWITCH - [COMBINATION[METER ASSY)(SEE[PAGE[01-34)



- (a) Disconnect the C12 and T10 connectors.
- (b) Measure the resistance according to the value (s) in the table below.

Standard:

Tester Connection	Condition	Specified@condition
C12-7 -[[10-1	Always	Below[] [Ω
C12-8 -[T10-3	Always	Below[] [Ω
C12-10 -[T10-2	Always	Below[] [Ω
C12-7 -[Body[ground	Always	10[k͡k͡k͡k͡kɪ] [higher
C12-8 -[Body[ground	Always	10[k͡k͡k͡k͡kɪ] [higher
C12-10 -[Body[ground	Always	10[k͡k͡k͡k͡kÞr[ˈħigher

NG

OK

REPLACE COMBINATION METER ASSY (SEE PAGE 71-21)